# **IEEE-NEMS** 2019

The 14th Annual IEEE International Conference on Nano/Micro Engineered and Molecular Systems













# Bangkok, Thailand, 11-14 April 2019 Bangkok Marriott Marquis Queen's Park

### **Key Info:**

- The conference has already confirmed 5 Plenary and 9 Keynote Speakers.
- The conference is now accepting Invited Session proposals. Please send Invited Session proposals to Prof. Cecil Chen (<a href="mailto:then@cityu.edu.hk">then@cityu.edu.hk</a>).
- A Special Issue based on author contributions to the conference will appear in the IEEE Trans. and Nanotechnology.
- Conference Website: <a href="https://ieee-nems.org/2019/">https://ieee-nems.org/2019/</a>.

### **Conference Scope:**

We invite contributions describing the latest scientific and technological research results in subjects including, but not limited to:

Micro/Nano Electro-Mechanical Systems (M/NEMS)

Micro/Nano/Molecular Fabrication

**Nanomaterials** 

Nonmaterial Based Devices and Systems

Nanophotonics and Nanoscale Imaging

Nanoscale Robotics, Assembly, and

Automation

Molecular Sensors, Actuators, and Systems

Micro/Nano Fluidics

Micro/Nano Mechanics

Nanobiology/Nanomedicine

## **Organizers:**

General Chair: Prof. Yufeng JIN, Peking Univ.,

China

General Co-Chair: Prof. Wen J. LI, City Univ.

of Hong Kong, Hong Kong

General Co-Chair: Prof. Jeffrey D.-J. YAO,

National Tsing Hua Univ., Taiwan

Program Chair: Prof. Cecil T.-H. CHEN, City

Univ. of Hong Kong, Hong Kong **Program Co-Chair:** Prof. Zhan YANG,

Soochow Univ., China

Awards Committee Chair: Prof. Jin-Woo KIM,

Univ. of Arkansas, USA

**Publications Chair:** Prof. Zhidong WANG, Chiba Institute of Technology, Japan

#### **Contact Us:**

Should you have any questions, please email to: <a href="mailto:t.sq.mgt@gmail.com">t.sq.mgt@gmail.com</a> (Please mention the conference name at the email subject.)

#### **Key Dates:**

Oct. 15, 2018: 2-page abstract submission

**Dec. 01, 2018:** Notification of paper acceptance **Jan. 15, 2019:** Final full paper submission (for

**IEEE Xplore database)**